

# LATS2016

17<sup>th</sup> IEEE Latin-American Test Symposium  
Foz do Iguazu, Brazil, 6<sup>th</sup> - 8<sup>th</sup> April 2016  
TTEP Day 9<sup>th</sup> April 2016



CALL FOR PAPERS

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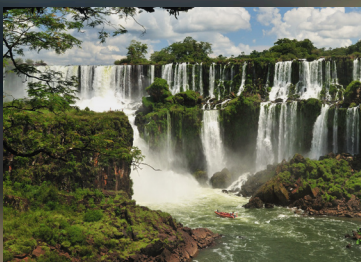
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the waterfalls near Foz do Iguaçu



the bird park allows to see birds in their natural environment

## CALL FOR PAPERS

The IEEE Latin-American Test Symposium (LATS, previously Latin-American Test Workshop - LATW) is a recongnized forum for test and fault tolerance professionals and technologists from all over the world, in particular from Latin America, to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. Presented papers are also published in the IEEE Xplore Digital Library. The best papers of the 17<sup>th</sup> LATS will be invited to re-submit to IEEE Design and Test of Computers, IEEE Transactions on Computer-Aided Design, Journal of Electronic Testing: Theory and Applications - JETTA (Springer) and Journal of Low Power Electronics - JOLPE (American Scientific Publishers).

## Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Design and Synthesis for Testability
- Design for Electromagnetic Compatibility
- Design for Reliable Embedded Software
- Design Verification/Validation
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation/EMI
- Hardening Techniques
- Software Fault-Tolerance
- Software On-Line Testing
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization
- Hardware Security

## Paper Submission Information:

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the symposium are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions must be done via the symposium's webpage: [www.lats.ttc-events.org](http://www.lats.ttc-events.org)

Authors should send papers in the IEEE format. Detailed instructions are available at the symposium's webpage. The Program Committee also welcomes proposals for panels and special topic sessions.

For additional information, please contact one of the Program Chairs:

**Matteo Sonza Reorda – Politecnico di Torino, Italy**

[matteo.sonzareorda@polito.it](mailto:matteo.sonzareorda@polito.it)

**Tiago Balen - Federal University of Rio Grande do Sul, Brazil**

[tiago.balen@ufrgs.br](mailto:tiago.balen@ufrgs.br)

**Submission Deadline (Title and Abstract):** November 25<sup>th</sup>, 2015

**Submission HARD DEADLINE (Full paper):** December 4<sup>th</sup>, 2015

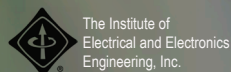
**Notification of Acceptance:** January 12<sup>th</sup>, 2016.

**Camera Ready:** January 26<sup>th</sup>, 2016.

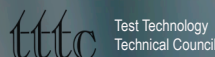
LATS 2016 will take place in the city of Foz do Iguaçu situated next to the famous falls on the Iguaçu River, which have a flow capacity equal to three times that of Niagara Falls. The exquisite Iguaçu Falls are also known as the Iguazu Falls and the Iguassu Falls and the magnificent spectacle of these 275 individual drops has awed tourists, locals and indigenous inhabitants for centuries. They originate from the Iguaçu River and are located on the border of Brazil and were chosen as one of the "New Natural Seven Wonders of the World". In fact, the Iguaçu Falls are what divides the river of the same name into its upper and lower portions, a fact that has given rise to several myths and legends as to their origin.

Besides the falls, Foz do Iguaçu offers famous fish-based cuisine and a famous zoological garden, focusing on tropical birds. where one may experience more than 1020 birds from about 150 different species in 16.5 hectares of lush Atlantic Rainforest.

## Technical Sponsor:



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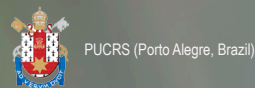


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